



10th *Inter-American Congress of Electron Microscopy* **2009** **CIASEM 2009**

1st *Congress of the Argentine Society of Microscopy*
SAMIC 2009



October 25-28, 2009

Ariston Hotel Convention Center
Pueyrredón 762
ROSARIO city, ARGENTINA

www.cab.cnea.gov.ar/ciasem2009

Contributions related to SEM, TEM, STM,
APFIM, confocal and optical microscopy
are welcome.

The following fields will be considered:

Physical and Materials Sciences
Biological & Medical Sciences
Instrumentation and Analysis
Applications

IMPORTANT DEADLINES

March 20, 2009: Pre-Registration and Submission of Short Abstract

April 17, 2009: Acceptance of the Short Abstract

June 15, 2009: Early Registration and Submission of Extended Abstract (2 pages)